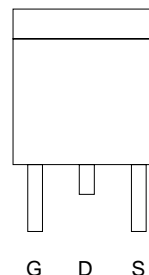


P-Channel Enhancement Mode MOSFET

Features

- -30V/-4A , $R_{DS(ON)} < 240m\Omega$ (typ.) @ $V_{GS} = -10V$
 $R_{DS(ON)} < 460m\Omega$ (typ.) @ $V_{GS} = -4.5V$
- Super High Dense Cell Design for Extremely Low $R_{DS(ON)}$
- Reliable and Rugged
- TO-252 Package

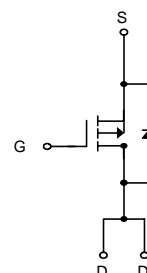
Pin Description



Top View of TO-252

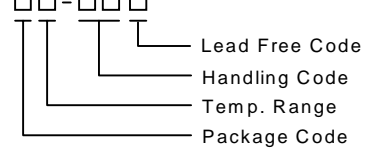

Applications

- Power Management in Notebook Computer ,
 Portable Equipment and Battery Powered
 Systems.



P-Channel MOSFET

Ordering and Marking Information

<p>APM3195P □□-□□□</p>  <p>Lead Free Code Handling Code Temp. Range Package Code</p>	<p>Package Code U : TO-252 Operating Junction Temp. Range C : -55 to 150°C Handling Code TU : Tube TR : Tape & Reel Lead Free Code L : Lead Free Device Blank : Original Device</p>
<p>APM3195P U :</p> 	<p>XXXXX - Date Code</p>

Absolute Maximum Ratings ($T_A = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Unit
V_{DSS}	Drain-Source Voltage	-30	V
V_{GSS}	Gate-Source Voltage	± 20	
I_D^*	Maximum Drain Current – Continuous	- 4	A
I_{DM}	Maximum Drain Current – Pulsed	-16	

* Surface Mounted on FR4 Board, $t \leq 10$ sec.

ANPEC reserves the right to make changes to improve reliability or manufacturability without notice, and advise customers to obtain the latest version of relevant information to verify before placing orders.

Absolute Maximum Ratings Cont. ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating	Unit
P_D	Maximum Power Dissipation	$T_A=25^\circ\text{C}$	W
		$T_A=100^\circ\text{C}$	
T_J	Maximum Junction Temperature	150	$^\circ\text{C}$
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
$R_{\theta JA}^*$	Thermal Resistance – Junction to Ambient	50	$^\circ\text{C/W}$

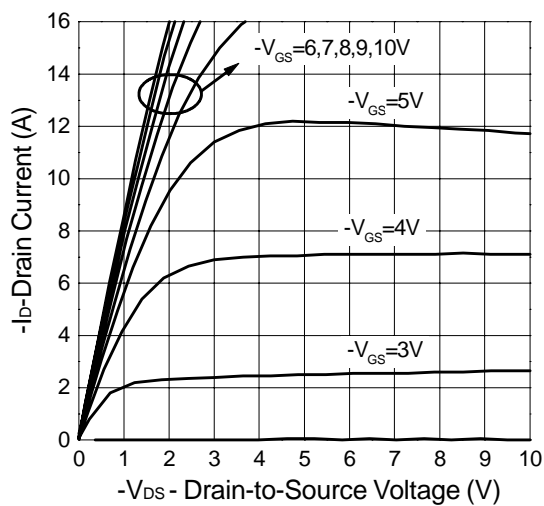
Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Condition	APM3195P			Unit
			Min.	Typ.	Max.	
Static						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _{DS} =-250μA	-30			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =-24V , V _{GS} =0V			-1	μA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =-250μA	-1	-1.5	-2	V
I _{GSS}	Gate Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA
R _{DS(ON)} ^a	Drain-Source On-state Resistance	V _{GS} =-10V , I _{DS} =-4A			240	mΩ
		V _{GS} =-4.5V , I _{DS} =-3A			460	
V _{SD} ^a	Diode Forward Voltage	I _{SD} =-0.5A , V _{GS} =0V		-0.8	-1.3	V
Dynamic ^b						
Q _g	Total Gate Charge	V _{DS} =-15V , I _{DS} =-4A V _{GS} =-10V		8.1	10.5	nC
Q _{gs}	Gate-Source Charge			2		
Q _{gd}	Gate-Drain Charge			1.1		
t _{d(ON)}	Turn-on Delay Time	V _{DD} =-15V , I _{DS} =-4A , V _{GEN} =-10V , R _G =6Ω		10	20	ns
T _r	Turn-on Rise Time			8	20	
t _{d(OFF)}	Turn-off Delay Time			25	50	
T _f	Turn-off Fall Time			5	15	
C _{iss}	Input Capacitance	V _{GS} =0V		507		pF
C _{oss}	Output Capacitance	V _{DS} =-25V		69		
C _{rss}	Reverse Transfer Capacitance	Frequency=1.0MHz		36		

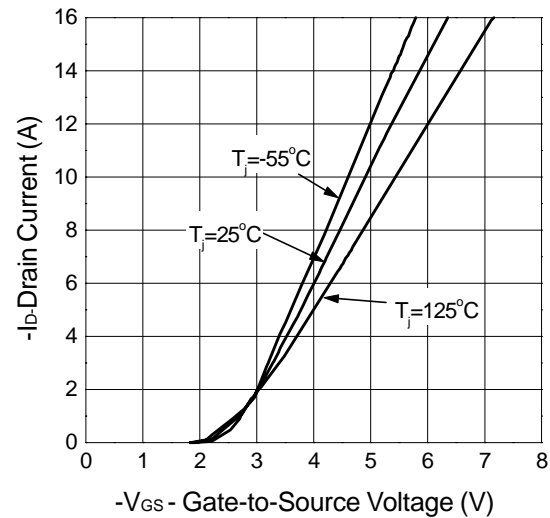
Notes
^a : Pulse test ; pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
^b : Guaranteed by design, not subject to production testing

Typical Characteristics

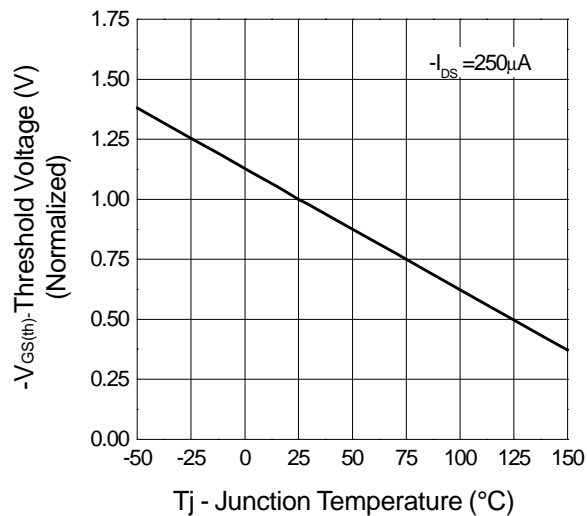
Output Characteristics



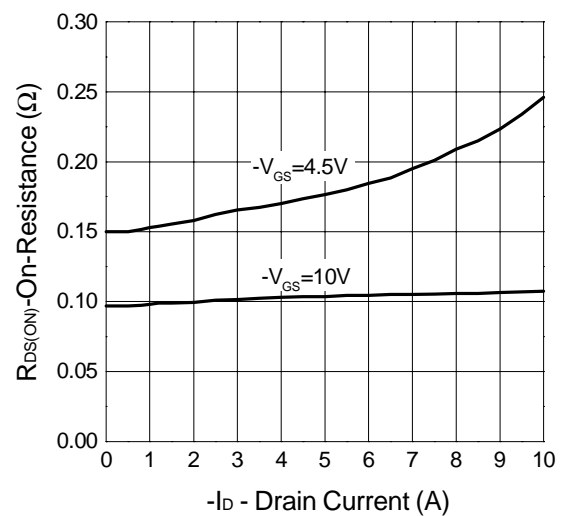
Transfer Characteristics



Threshold Voltage vs. Junction Temperature

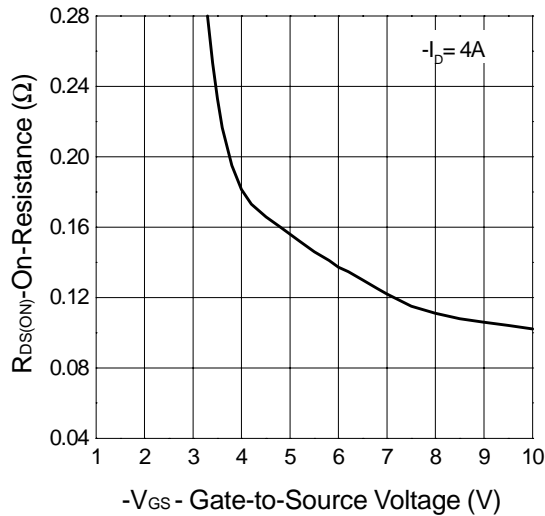


On-Resistance vs. Drain Current

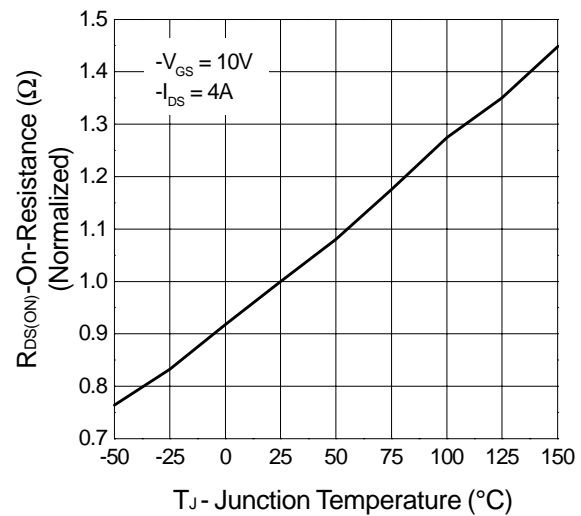


Typical Characteristics

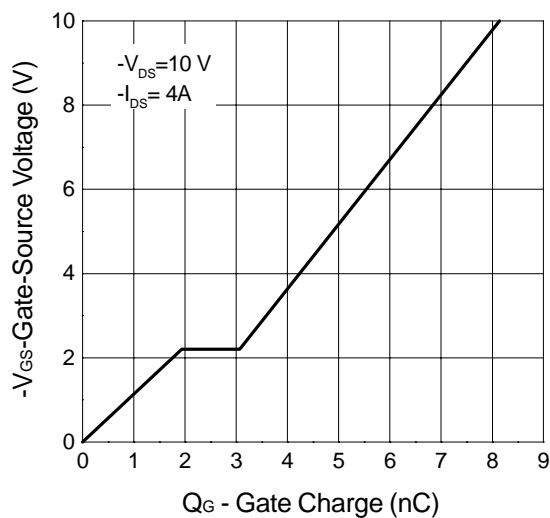
On-Resistance vs. Gate-to-Source Voltage



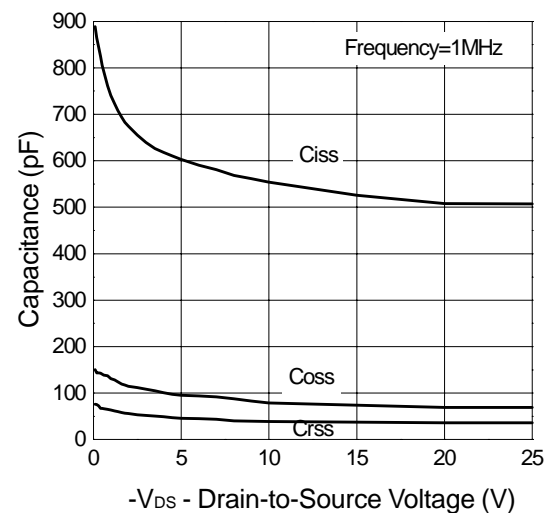
On-Resistance vs. Junction Temperature



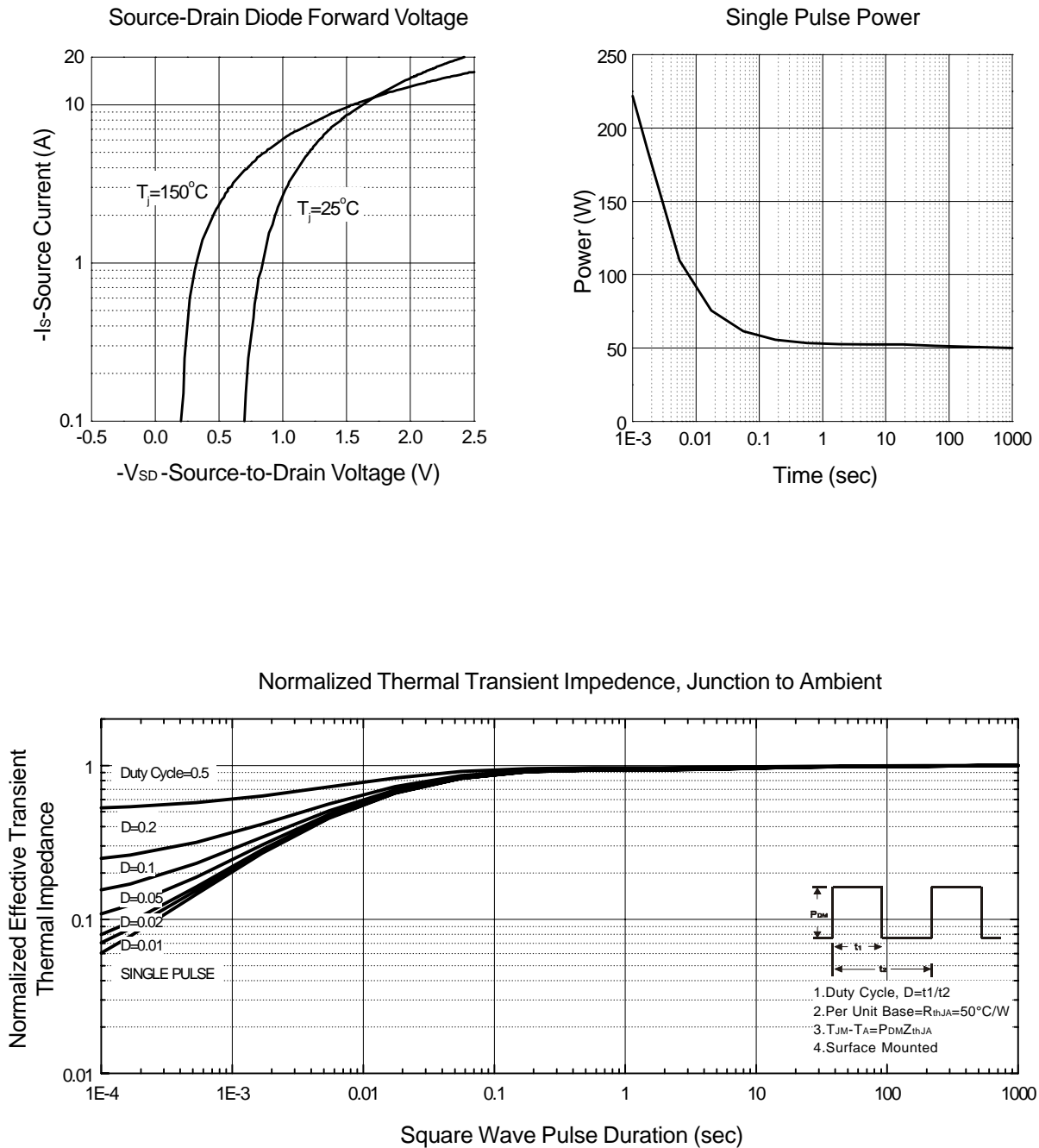
Gate Charge



Capacitance

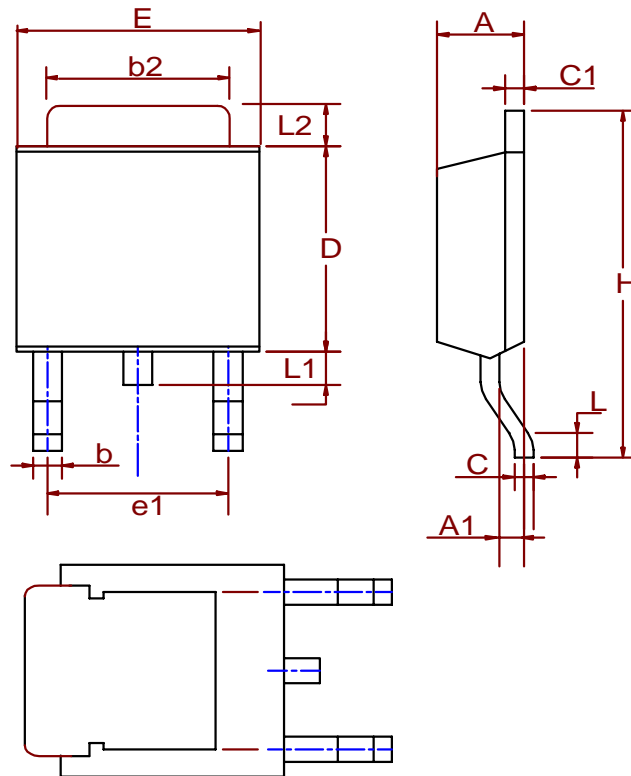


Typical Characteristics



Packaging Information

TO-252(Reference JEDEC Registration TO-252)

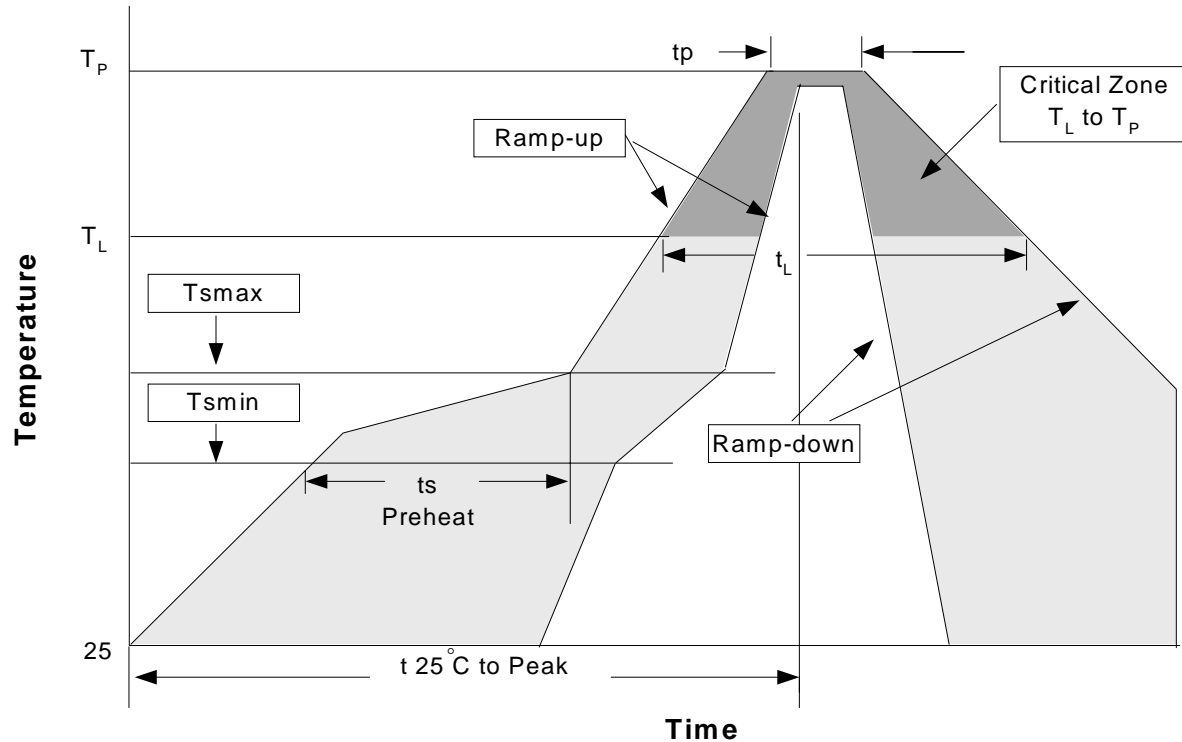


Dim	Millimeters		Inches	
	Min.	Max.	Min.	Max.
A	2.18	2.39	0.086	0.094
A1	0.89	1.27	0.035	0.050
b	0.508	0.89	0.020	0.035
b2	5.207	5.461	0.205	0.215
C	0.46	0.58	0.018	0.023
C1	0.46	0.58	0.018	0.023
D	5.334	6.22	0.210	0.245
E	6.35	6.73	0.250	0.265
e1	3.96	5.18	0.156	0.204
H	9.398	10.41	0.370	0.410
L	0.51		0.020	
L1	0.64	1.02	0.025	0.040
L2	0.89	2.032	0.035	0.080

Physical Specifications

Terminal Material	Solder-Plated Copper (Solder Material : 90/10 or 63/37 SnPb), 100%Sn
Lead Solderability	Meets EIA Specification RSI86-91, ANSI/J-STD-002 Category 3.

Reflow Condition (IR/Convection or VPR Reflow)



Classification Reflow Profiles

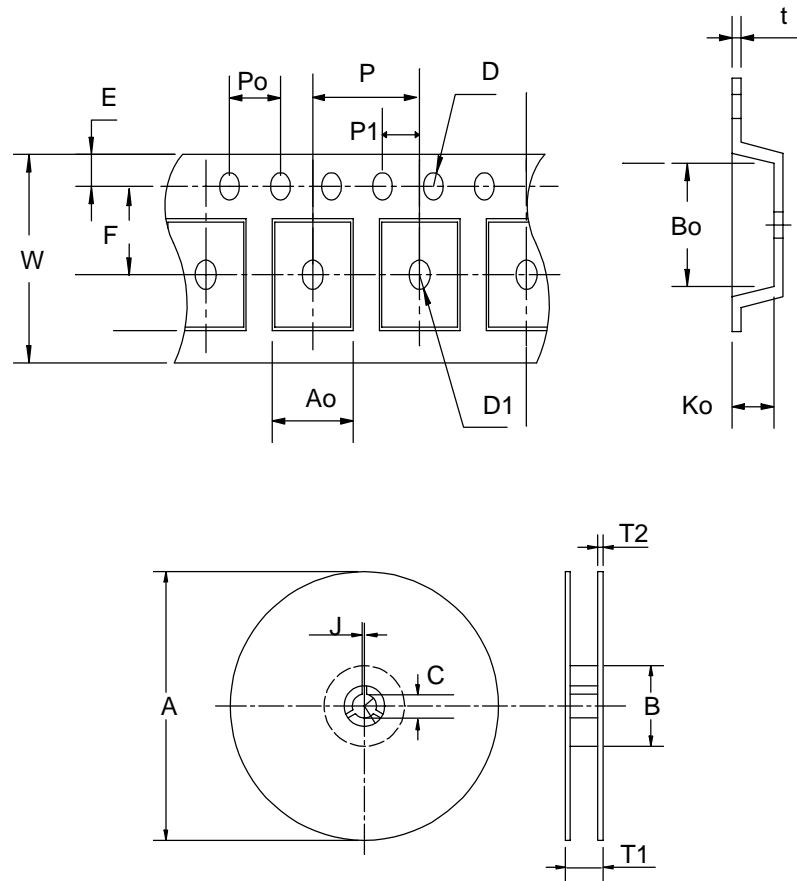
Profile Feature	Sn-Pb Eutectic Assembly		Pb-Free Assembly	
	Large Body	Small Body	Large Body	Small Body
Average ramp-up rate (T_L to T_P)	3°C/second max.		3°C/second max.	
Preheat				
- Temperature Min (T_{smin})	100°C		150°C	
- Temperature Mix (T_{smax})	150°C		200°C	
- Time (min to max)(t_s)	60-120 seconds		60-180 seconds	
T_{smax} to T_L			3°C/second max	
- Ramp-up Rate				
T_{smax} to T_L				
- Temperature(T_L)	183°C		217°C	
- Time (t_L)	60-150 seconds		60-150 seconds	
Peak Temperature(T_P)	225 +0/-5°C	240 +0/-5°C	245 +0/-5°C	250 +0/-5°C
Time within 5°C of actual Peak Temperature(t_p)	10-30 seconds	10-30 seconds	10-30 seconds	20-40 seconds
Ramp-down Rate	6°C/second max.		6°C/second max.	
Time 25°C to Peak Temperature	6 minutes max.		8 minutes max.	

Note: All temperatures refer to topside of the package. Measured on the body surface.

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	MIL-STD-883D-2003	245°C, 5 SEC
HOLT	MIL-STD 883D-1005.7	1000 Hrs Bias @ 125°C
PCT	JESD-22-B, A102	168 Hrs, 100% RH, 121°C
TST	MIL-STD 883D-1011.9	-65°C ~ 150°C, 200 Cycles

Carrier Tape & Reel Dimensions



Application	A	B	C	J	T1	T2	W	P	E
TO-252	330 ± 3	100 ± 2	13 ± 0.5	2 ± 0.5	16.4 + 0.3 - 0.2	2.5 ± 0.5	16 + 0.3 - 0.1	8 ± 0.1	1.75 ± 0.1
	F	D	D1	Po	P1	Ao	Bo	Ko	t
	7.5 ± 0.1	1.5 ± 0.1	1.5 ± 0.25	4.0 ± 0.1	2.0 ± 0.1	6.8 ± 0.1	10.4 ± 0.1	2.5 ± 0.1	0.3 ± 0.05

(mm)

Cover Tape Dimensions

Application	Carrier Width	Cover Tape Width	Devices Per Reel
TO- 252	16	13.3	2500

Customer Service

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